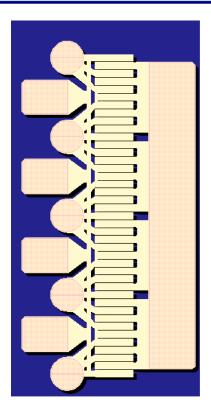
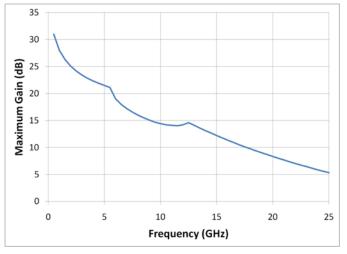


### 25 Watt Discrete Power GaN on SiC HEMT



Bias conditions: Vd = 28 V, Idq = 500 mA, Vg = -3.6 V Typical



### **Key Features**

- Frequency Range: DC 18 GHz
- 43.9 dBm Nominal Psat at 3 GHz
- 56% Maximum PAE
- 17.8 dB Nominal Power Gain
- Bias: Vd = 28 32 V, Idq = 500 mA, Vg = -3.6 V Typical
- Technology: 0.25 um Power GaN on SiC
- Chip Dimensions: 0.82 x 1.44 x 0.10 mm

### **Primary Applications**

- Defense & Aerospace
- Broadband Wireless

### **Product Description**

The TriQuint TGF2023-05 is a discrete 5.0 mm GaN on SiC HEMT which operates from DC-18 GHz. The TGF2023-05 is designed using TriQuint's proven 0.25um GaN production process. This process features advanced field plate techniques to optimize microwave power and efficiency at high drain bias operating conditions.

The TGF2023-05 typically provides 43.9 dBm of saturated output power with power gain of 17.8 dB at 3 GHz. The maximum power added efficiency is 56% which makes the TGF2023-05 appropriate for high efficiency applications.

Datasi pet subject o change without notice.

mwiaid

Lead-free and RoHS compliant

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**Table I**Absolute Maximum Ratings <u>1</u>/

Symbol	Parameter	Value	Notes
Vd	Drain Voltage	40 V	<u>2/</u>
Vg	Gate Voltage Range	-50 to 0 V	
Vdg	Drain-Gate Voltage	80 V	
ld	Drain Current	5 A	<u>2/</u>
lg	Gate Current	28 mA	
Pin	Input Continuous Wave Power	37 dBm	<u>2/</u>
Tch	Channel Temperature	200 °C	

- 1/ These ratings represent the maximum operable values for this device. Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device and / or affect device lifetime. These are stress ratings only, and functional operation of the device at these conditions is not implied.
- 2/ Combinations of supply voltage, supply current, input power, and output power shall not exceed the maximum power dissipation listed in Table IV.

### Table II Recommended Operating Conditions

Symbol	Parameter	Value
Vd	Drain Voltage	28 - 32 V
ldq	Drain Current	500 mA
Id_Drive	Drain Current under RF Drive	1500 mA
Vg	Gate Voltage	-3.6 V





## Table III

### RF Characterization Table 1/

Bias: Vd = 28 V, Idq = 500 mA, Vg = -3.6V Typical

SYMBOL	PARAMETER	3 GHz	6 GHz	10 GHz	14 GHz	UNITS
Power Tuned:						
Psat	Saturated Output Power	43.9	43.2	43.0	41.6	dBm
PAE	Power Added Efficiency	56	56	49	39	%
Gain	Power Gain	17.8	11.9	9.4	6.1	dB
Efficiency Tuned:						
Psat	Saturated Output Power	42.6	41.5	42.7	41.6	dBm
PAE	Power Added Efficiency	62	62	51	40	%
Gain	Power Gain	17.1	12.5	9.7	6.0	dB

SYMBOL	PARAMETER	3 GHz	6 GHz	10 GHz	14 GHz	UNITS
Power Tuned:						
Rp <u>2</u> /	Parallel Resistance	79.3	81.9	61.5	49.9	Ω•mm
Cp <u>2</u> /	Parallel Capacitance	0.524	0.348	0.426	0.432	pF/mm
Efficiency Tuned:						
Rp <u>2</u> /	Parallel Resistance	153	171	72.1	53.1	Ω•mm
Cp <u>2</u> /	Parallel Capacitance	0.426	0.372	0.414	0.472	pF/mm

1/ Values in this table are engineering estimates scaled from measurements on the 1.25 mm GaN/SiC unit cell (see TGF2023-01 datasheet)

<u>2</u>/ Large signal equivalent output network (normalized) (see figure, pg 7)

# 3 TriQuint Semiconductor. www. triquint.com (972)994-6465 Tax (972)994-6504 Info-stmw@tqs.com





### Table IV

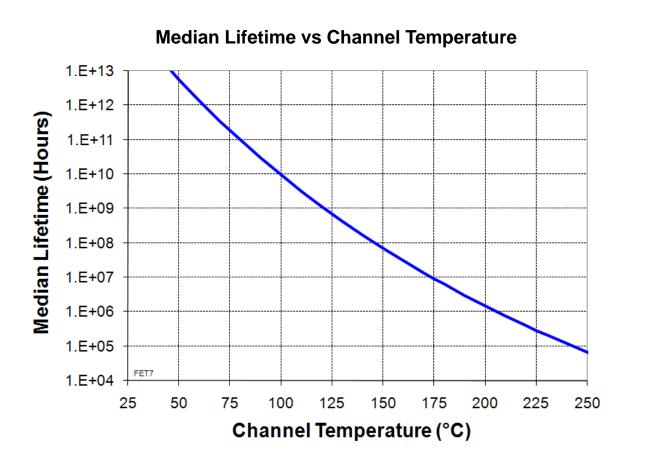
### Power Dissipation and Thermal Properties 1/

Parameter	Test Conditions	Value	Notes
Maximum Power Dissipation	Tbaseplate = 70 °C	Pd = 32.2 W Tchannel = 200 °C Tm = 1.5E+6 Hrs	<u>2</u> /
Thermal Resistance, θjc	Vd = 28 V Id = 500 mA Pd = 14 W Tbaseplate = 70 °C	θjc = 4.0 (°C/W) Tchannel = 126 °C Tm = 6.4E+8 Hrs	
Thermal Resistance, θjc Under RF Drive	Vd = 28 V Id = 1540 mA Pout = 43.9 dBm Pd = 19.0 W Tbaseplate = 70 °C	θjc = 4.0 (°C/W) Tchannel = 146 °C Tm = 1.0E+8 Hrs	
Mounting Temperature	30 Seconds	320 °C	
Storage Temperature		-65 to 150 °C	

- 1/ Assumes eutectic attach using 1mil thick 80/20 AuSn mounted to a 10mil CuMo Carrier Plate
- 2/ Channel operating temperature will directly affect the device median lifetime. For maximum life, it is recommended that channel temperatures be maintained at the lowest possible levels.





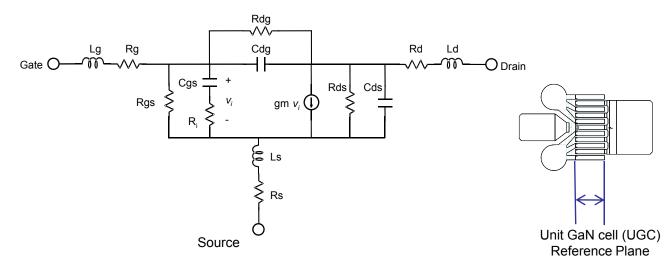




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Linear Model for 1.25 mm Unit GaN Cell (UGC)



MODEL PARAMETER	Vd=28V Idq=125mA	UNITS
Rg	0.78	Ω
Rs	0.13	Ω
Rd	1.28	Ω
gm	0.270	S
Cgs	1.79	pF
Ri	0.26	Ω
Cds	0.308	pF
Rds	123.6	Ω
Cgd	0.064	pF
Tau	2.78	pS
Ls	0.0058	nH
Lg	-0.013	nH
Ld	0.018	nH
Rgs	8900	Ω
Rgd	1730000	Ω

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Info

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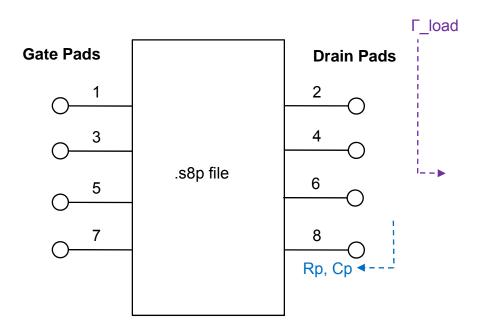
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### **Complete 5mm GaN HEMT Linear Model**

Includes 4 UGC, 5 vias, and 8 bonding pads

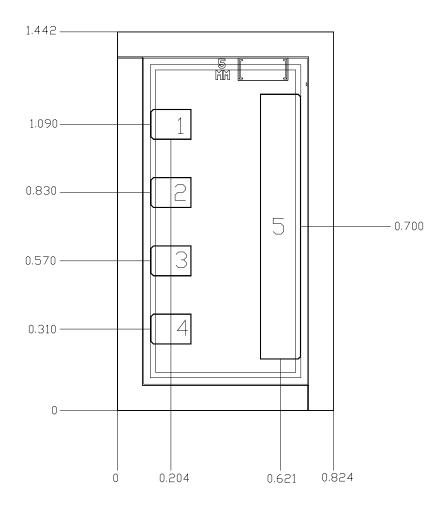








**Mechanical Drawing** 



Units: millimeters Thickness: 0.100 Die x,y size tolerance: +/- 0.050 Chip edge to bond pad dimensions are shown to center of pad Ground is backside of die

Bond Pad #1, #2, #3, #4	Vg	0.154 x 0.115
Bond Pad #5	Vd	0.154 x 1.010

GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.





### **Assembly Notes**

Component placement and adhesive attachment assembly notes:

- Vacuum pencils and/or vacuum collets are the preferred method of pick up.
- Air bridges must be avoided during placement.
- The force impact is critical during auto placement.
- Organic attachment (i.e. epoxy) can be used in low-power applications.
- Curing should be done in a convection oven; proper exhaust is a safety concern.

Reflow process assembly notes:

- Use AuSn (80/20) solder and limit exposure to temperatures above 300°C to 3-4 minutes, maximum.
- An alloy station or conveyor furnace with reducing atmosphere should be used.
- Do not use any kind of flux.
- · Coefficient of thermal expansion matching is critical for long-term reliability.
- · Devices must be stored in a dry nitrogen atmosphere.

Interconnect process assembly notes:

- Ball bonding is the preferred interconnect technique, except where noted on the assembly diagram.
- · Force, time, and ultrasonics are critical bonding parameters.
- Aluminum wire should not be used.
- Devices with small pad sizes should be bonded with 0.0007-inch wire.

### **Ordering Information**

Part	ECCN	Package Style
TGF2023-05	3A001.b.3.b	GaN on SiC Die

GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.

